



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Stefan Peter Hau-Riege

Docket No.: IL-11154

Serial No.: 10/783,520

Group Art Unit: 2877

Filed : February 20, 2004

Examiner: S. Nguyen

For : Method For Characterizing Mask Defects Using
Image Reconstruction From X-Ray Diffraction Patterns

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING UNDER 37 CFR 1.8(a)

I hereby certify that the *attached* correspondence comprising:

1. Amendment (21 pages);
2. Drawing Submission Cover Sheet;
3. Six Sheets of Replacement Drawings;
4. Petition for Extension (in duplicate);
5. Certificate of Mailing; and
6. Return Postcard;

is being deposited with the United States Postal Service as first class mail in an envelope addressed to:

Mail Stop Amendment
Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

on December 26, 2006

John P. Wooldridge

(Type or print name of person mailing paper)

(Signature of person mailing paper)